

AMENDMENTS TO THE CLAIMS

1. (Canceled)

2. (Currently Amended) A temperature control device used for an electronic device testing apparatus for conducting a test on an electronic device to be tested by sending a test pattern to the electronic device to be tested and detecting a response pattern thereto, comprising: a temperature adjusting device provided to contact with said electronic device to be tested; and

a power control means for controlling power consumption of said temperature adjusting device, so that total power of a power consumption of said electronic device by said test pattern and a power consumption of said temperature adjusting device becomes a constant value. The temperature control device as set forth in claim 1, wherein said power control means comprises

a power consumption pattern prediction portion for predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device;

a power consumption canceling pattern generation portion for generating a power consumption canceling pattern for canceling a power consumption pattern in said electronic device to be tested; and

a power consumption canceling pattern transmission portion for sending said power consumption canceling pattern to said temperature adjusting device.

3. (Canceled)

4. (Currently Amended) ~~The temperature control device as set forth in claim 1~~ claim 2, wherein temperature change characteristics by a power consumption of said temperature adjusting device are equal to or close to those by a power consumption of said electronic device to be tested.

5. (Original) The temperature control device as set forth in claim 4, wherein a heat capacity of said temperature adjusting device is equal to or close to that of said electronic device to be tested.

6. (Canceled)

7. (Currently Amended) A temperature control method for conducting a test on an electronic device to be tested by transmitting a test pattern to said electronic device to be tested and detecting a response pattern thereto, comprising the steps of:

bringing a temperature adjusting device to said electronic device to be tested; and
controlling a power consumption of said temperature adjusting device, so that a total power of a power consumption of said electronic device to be tested and a power consumption of said temperature adjusting device becomes a constant value. ~~The temperature control method as set forth in claim 6,~~ wherein said step for controlling the power consumption comprises steps of
predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device to be tested;

generating a power consumption canceling pattern for canceling a power consumption in said electronic device to be tested; and

transmitting said power consumption canceling pattern to said temperature adjusting device.

8. (Canceled)

9. (Currently Amended) An electronic device testing handler, comprising:

a pusher for pressing an electronic device to be tested against a contact terminal, to which a test pattern is input; and

a temperature adjusting device provided to said pusher so as to contact with said electronic device to be tested; and

~~a controller for controlling wherein~~ a power consumption of said temperature adjusting device ~~is controlled~~, so that total power of a power consumption of said electronic device to be tested by said test pattern and a power consumption of said temperature adjusting device becomes a constant value,

wherein said controller comprises:

a power consumption pattern prediction portion for predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device;

a power consumption canceling pattern generation portion for generating a power consumption canceling pattern for canceling a power consumption pattern in said electronic device to be tested; and

a power consumption canceling pattern transmission portion for sending said power consumption canceling pattern to said temperature adjusting device.

10. (Canceled)

11. (Currently Amended) An electronic device testing apparatus, comprising:

a test pattern generation means for generating a predetermined test pattern;

a test pattern transmission means for transmitting a test pattern generated by said test pattern generation means to a contact terminal, against which a terminal of an electronic device to be tested is pressed;

a determination means for evaluating said electronic device to be tested based on a response pattern to said test pattern; and

a power control means for controlling a power consumption of said temperature adjusting device, so that total power of a power consumption of said electronic device to be tested by said test pattern and a power consumption of a temperature adjusting device provided for contacting with said electronic device to be tested becomes a constant value. ~~The electronic device testing apparatus as set forth in claim 10,~~ wherein said power control means comprises:

a power consumption pattern prediction portion for predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device to be tested;

a power consumption canceling pattern generation portion for generating a power consumption canceling pattern for canceling a power consumption pattern in said electronic device to be tested; and

a power consumption canceling pattern transmission portion for transmitting said power consumption canceling pattern to said temperature adjusting device.

12. (Canceled)

13. (Currently Amended) An electronic device testing method for conducting a test on an electronic device to be tested by transmitting a predetermined test pattern to said electronic device to be tested via a contact terminal and detecting a response pattern thereto in a state of pressing a terminal of said electronic device to said contact terminal, comprising the steps of:

bringing a temperature adjusting device contact with said electronic device to be tested;

controlling a power consumption of said temperature adjusting device, so that total power of a power consumption of said electronic device to be tested by said test pattern and a power consumption of said temperature adjusting device becomes a constant value; and

evaluating said electronic device to be tested based on a response pattern to said test pattern,

wherein said step for controlling the power consumption comprises steps of:

predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device to be tested;

generating a power consumption canceling pattern for canceling a power consumption in said electronic device to be tested; and

transmitting said power consumption canceling pattern to said temperature adjusting device.

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14.-24. (Canceled)